Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/654,553	HAYASHI ET AL.	
Examiner	Art Unit	
Drew E. Becker	1761	

	SEARCHED					
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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